

Search Notes

Application/Control No.

10/814,369

Examiner

/Yonel Beaulieu/

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

3661

SEARCHED

Class	Subclass	Date	Examiner
701	3	5/30/2007	YB
	13-18		
	1		
244	158.1		
	75.1		
	76 R		
340	945		
702	144		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST	5/30/2007	YB